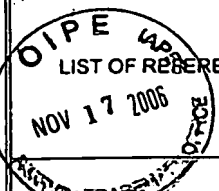


Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 246070US26		SERIAL NO. 10/722,602	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Kouji MITSUHASHI, et al.			
				FILING DATE November 28, 2003		GROUP 1763	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
/RD/	AA	6,444,083	09-03-2002	Steger et al.			
	AB	6,896,785 B2	05-24-2005	Shatrov et al.			
	AC	2003/0150419 A1	08-14-2003	Daragheh et al.			
	AD	2006/0134919 A1	06-22-2006	Hamelin et al.			
	AE	2004/0060779 A1	04-01-2004	Kreger, Charles			
	AF	6,413,578	07-02-2002	Stowell et al.			
	AG	5,367,838	11-29-1994	Visaisouk et al.			
	AH	6,863,594 B2	03-08-2005	Preising, Paul-Eric			
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	AJ	4,649,858	03-17-1987	Sakai et al.			
	AK						
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
/RD/	AO	KR2002-0027373	04-13-2002	Republic of Korea (corresponding to USP 6,444,083)			
/RD/	AP	KR1998-063542	10-07-1998	Republic of Korea (corresponding to USP 6,120,640 previously filed)			
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
/RD/	AW	Kim, Hee Jee, "Plasma-Sprayed Alumina-Yttria Ceramic Coatings for Cavitation-Erosion Protection," September 1989, pp 139-146					
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner				/Rakesh Dhingra/		Date Considered 04/28/2007	
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
/RD/	AO	JP 06-196548	07-15-1994	Japan (with English Abstract)			x
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner				/Rakesh Dhingra/		Date Considered 04/28/2007	
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